Electronic Supplementary Information (ESI) for

## Solvothermal Synthesis of Cesium Lead Halide Perovskite Nanowires with Ultra-High Aspect Ratios for High-Performance Photodetectors

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Figure S1.Typical SEM image of the as-prepared CsPbI<sub>3</sub> microrods.

**Table S1** .The time-resolved PL decay curve of the CsPbX3 NWs can be describedby two-exponential fitting: I(t)=A+B1\*exp-i/T1+B2\*exp-i/T2

PL(nm)	T1(ns)	Amplitude 1	T2 (ns)	Amplitude 2	<t> (ns)</t>
410 nm	2.46	0.49	15.73	0.51	4.3
520 nm	5.28	0.22	24.26	0.78	13.6



**Figure S2**. The PL intensity change of soild CsPbBr<sub>3</sub> NWs powder after stored in air for different times. For the stability testing of NWs powder, the as-prepared CsPbBr<sub>3</sub>/n-hexane solutions with high NW concentration were dropped onto a piece of glass sheet with 1\*1\*0.1 cm groove. The n-hexane solvent was completely volatilized to form the NWs powder. Then the glass sheet was stored in air at room temperature (25°C) with humidity of ~40%. The PL intensity remains ~50% of the original intensity even after 75 h of storage in air.



**Figure S3**. XRD pattern of CsPbBr<sub>3</sub> NWs after stored in air for 4 months. (inset) Photo of the XRD sample stage after being left at room temperature (10-25 °C) for 4 months in the air humidity range from 35% to 45%, showing bright green light under a UV lamp irradiation.



**Figure S4**. (a) TEM image of CsPbBr<sub>3</sub> NWs and NPLs prepared at 100 °C for about 48 h. (b) TEM image of CsPbCl<sub>3</sub> NWs and NPLs prepared at 100 °C for about 48 h.



**Figure S5**. Photocurrent as a function of light intensity and corresponding fitting curve using the power law for CsPbCl<sub>3</sub> NWs device.

It can be seen that the optical power value we selected did not make the photocurrent reach saturation value. The corresponding dependence can be fitted to a power law,  $I_p \propto P^{\theta}$ , the exponent  $\theta$  determines by the photocurrent response to light intensity. The fitting gives a sub-linear behavior of  $\theta = 0.55$ . This result may indicate a complex process of electron-hole generation, recombination, and trapping within a semiconductor.



**Figure S6**.  $I_{ph}$ -*t* photoresponse of CsPbCl<sub>3</sub> NWs device after two day placed in the air environment (temperature and air humidity are 25 °C and 40%) with the same test parameters (bias voltages at 8 V, light intensity=0.985 mW/cm<sup>2</sup>).



**Figure S7**. *I-V* curves of a CsPbBr<sub>3</sub> NWs photodetector measured under dark and light conditions. The light intensity increases from 0.011 to 1.267 mW/cm<sup>2</sup>.



**Figure S8**.  $I_{ph}$ -*t* photoresponse of CsPbBr<sub>3</sub> NWs device under bias voltages at 6 V (light intensity=1.147 mW/cm<sup>2</sup>).



**Figure S9**. Rise and decay times of the CsPbBr<sub>3</sub> NWs photodetector device (light intensity=1.147 mW/cm<sup>2</sup>).